Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/616,492	LEE, YAO-SHENG
Γ	Examiner	Art Unit
	Binh X. Tran	1765

	SEARCHED		
Class	Subclass	Date	Examiner
216	· 58	11/15/2005	вт
216	63	11/15/2005	ВТ
216	68	11/15/2005	вт
216	74	11/15/2005	ВТ
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INT	ERFERENC	RENCE SEARCHED		
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Update search using USPAT, USPG- PUB, JPO, EPO, DERWENT databases	11/15/2005	вт